


<b>Search Notes</b>  	<b>Application/Control No.</b>  10754701	<b>Applicant(s)/Patent Under Reexamination</b>  SEMICONDUCTOR ENERGY LAB
	<b>Examiner</b>  DAO H NGUYEN	<b>Art Unit</b>  2818

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
EAST (USPAT; US-PGPUB; USOCR; FPRS; EPO; JPO; IBM_TDB) See attached search history	04/06/2008	DHN

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner